Defect- and Interface-Induced Dielectric Loss in $ZnFe_2O_4$/ZnO/C Electromagnetic Wave Absorber

Hao Shen [1], Zhen Wang [1], Chun Wang [2], Pengfei Zou [1], Zhaoyang Hou [1], Chunlong Xu [1,*] and Hongjing Wu [3,*]

[1] Department of Applied Physics, School of Science, Chang'an University, Xi'an 710064, China
[2] School of Science, Xi'an Shiyou University, Xi'an 710064, China
[3] MOE Key Laboratory of Material Physics and Chemistry Under Extraordinary Conditions, School of Physical Science and Technology, Northwestern Polytechnical University, Xi'an 710072, China
* Correspondence: chunlongxu@chd.edu.cn (C.X.); wuhongjing@nwpu.edu.cn (H.W.)

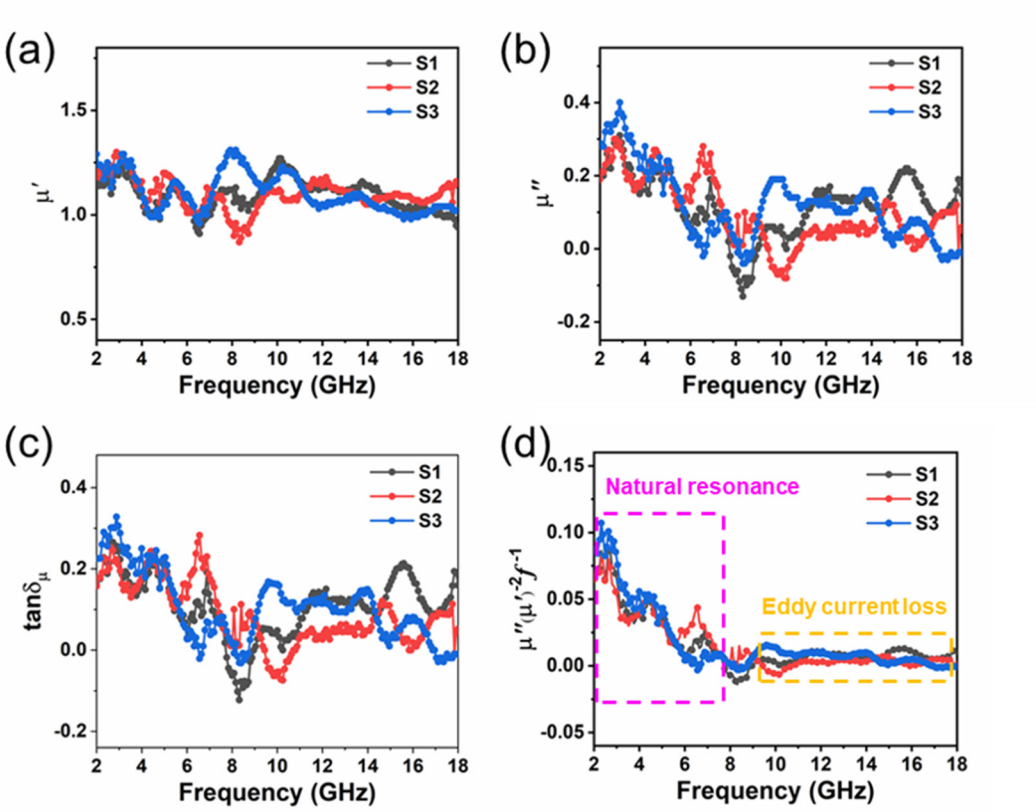

Figure S1. Frequency dependence of μ' (**a**), μ'' (**b**), magnetic loss tangents (**c**) and C_0 values (**d**) of S1–S3.

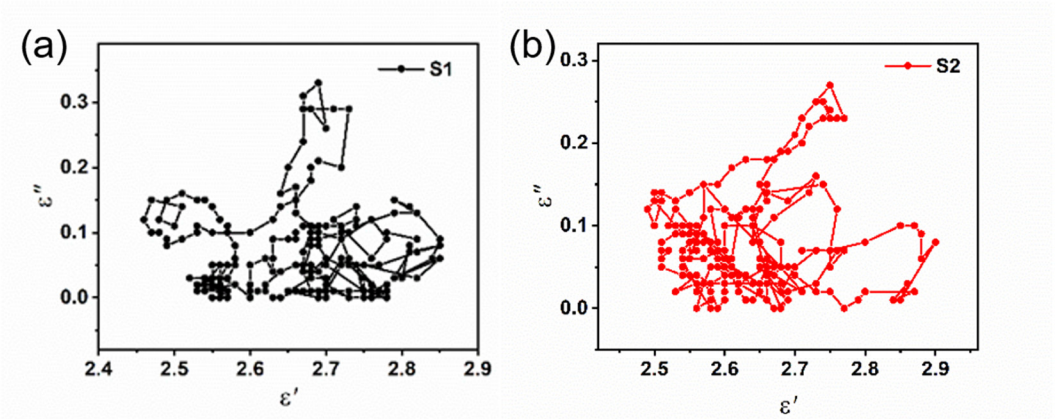

Figure S2. Cole-Cole plots of S1 (a) and S2 (b).

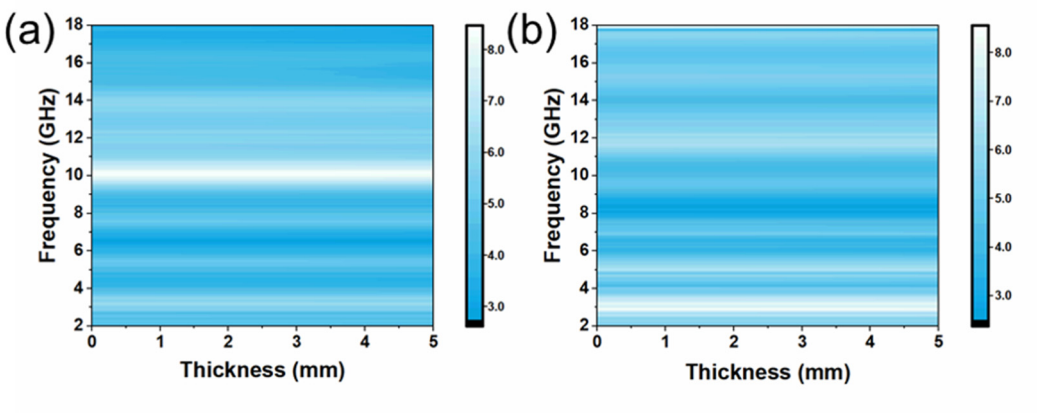

Figure S3. The calculated delta value maps of S1 (a) and S2 (b).